TOSHIBA Field Effect Transistor Silicon N Channel MOS Type

# SSM3K04FU

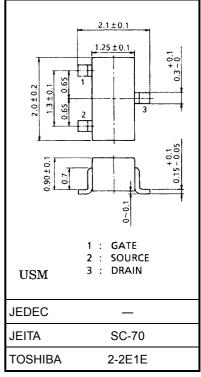
#### **High Speed Switch Applications**

Unit: mm

- With built-in gate-source resistor:  $R_{GS} = 1 M\Omega$  (typ.)
- 2.5 V gate drive
- Low gate threshold voltage:  $V_{th} = 0.7 \sim 1.3 \text{ V}$
- Small package

#### **Maximum Ratings (Ta = 25°C)**

Characteristics	Symbol	Rating	Unit
Drain-source voltage	$V_{DS}$	20	V
Gate-source voltage	$V_{GSS}$	10	V
DC drain current	I <sub>D</sub>	100	mA
Drain power dissipation	$P_{D}$	100	mW
Channel temperature	T <sub>ch</sub>	150	°C
Storage temperature range	T <sub>stg</sub>	-55~150	°C

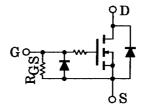


Weight: 0.006 g (typ.)

#### Marking



## **Equivalent Circuit**



## **Electrical Characteristics (Ta = 25°C)**

Characteristics		Symbol	Test Condition	Min	Тур.	Max	Unit	
Gate leakage current		I <sub>GSS</sub>	$V_{GS} = 10 \ V, \ V_{DS} = 0$	_	_	15	μА	
Drain-source breakdown voltage		V (BR) DSS	$I_D = 100 \ \mu A, \ V_{GS} = 0$	20	_	_	V	
Drain cut-off currer	nt	I <sub>DSS</sub>	$V_{DS} = 20 \ V, \ V_{GS} = 0$	_	_	1	μΑ	
Gate threshold volt	age	V <sub>th</sub>	V <sub>DS</sub> = 3 V, I <sub>D</sub> = 0.1 mA	0.7	_	1.3	V	
Forward transfer ad	dmittance	Y <sub>fs</sub>	V <sub>DS</sub> = 3 V, I <sub>D</sub> = 10 mA	25	50	_	mS	
Drain-source ON resistance		R <sub>DS</sub> (ON)	$I_D$ = 10 mA, $V_{GS}$ = 2.5 V	_	4	12	Ω	
Input capacitance		C <sub>iss</sub>	$V_{DS} = 3 \text{ V}, V_{GS} = 0, f = 1 \text{ MHz}$	_	11.0	_	pF	
Reverse transfer capacitance		C <sub>rss</sub>	$V_{DS} = 3 \text{ V}, V_{GS} = 0, f = 1 \text{ MHz}$	_	3.3	_	pF	
Output capacitance		Coss	$V_{DS} = 3 \text{ V}, V_{GS} = 0, f = 1 \text{ MHz}$	_	9.3	_	pF	
Switching time	Turn-on time	t <sub>on</sub>	$V_{DD} = 3 \text{ V}, I_D = 10 \text{ mA}, V_{GS} = 0~2.5 \text{ V}$	_	0.16	_	μ\$	
	Turn-off time	t <sub>off</sub>	$V_{DD} = 3 \text{ V}, I_D = 10 \text{ mA}, V_{GS} = 0 \sim 2.5 \text{ V}$	_	0.19	_		
Gate-source resistor		R <sub>GS</sub>	V <sub>GS</sub> = 0~10 V	0.7	1.0	1.3	ΜΩ	

# **Switching Time Test Circuit**

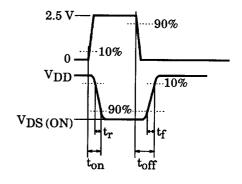
(a) Test circuit

 $\begin{array}{c|c} 2.5 \, \mathrm{V} & \text{II} & \text{OUT} \\ \hline 0 & \text{II} & \text{CO} & \\ \hline 10 \, \mu \mathrm{s} & \text{CO} & \text{CO} \\ \hline V_{\mathrm{IN}} & \text{m} & \text{m} & \text{V}_{\mathrm{DD}} \end{array}$ 

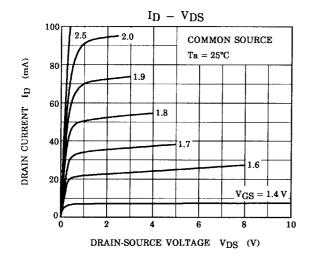
 $\begin{array}{c|c} I_{\hbox{\scriptsize D}} & \text{\scriptsize OUT} & V_{\hbox{\scriptsize DD}} = 3 \text{ V} \\ \hline & \text{\scriptsize D.U.} \le 1\% \\ \hline & \text{\scriptsize VIN} : t_{\hbox{\scriptsize r}}, t_{\hbox{\scriptsize f}} < 5 \text{ ns} \\ & (Z_{\hbox{\scriptsize out}} = 50 \Omega) \\ \hline & \hbox{\scriptsize COMMON SOURCE} \\ \hline & T_{\hbox{\scriptsize A}} = 25^{\circ}\text{C} \end{array}$ 

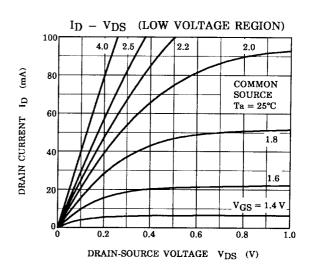
(b) V<sub>IN</sub> V<sub>GS</sub>

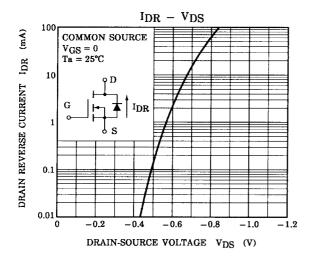
(c) V<sub>OUT</sub> V<sub>DS</sub>

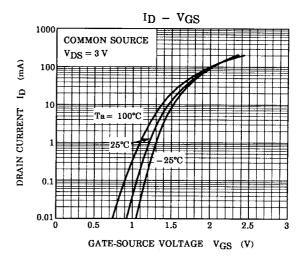


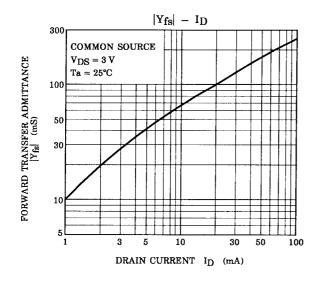
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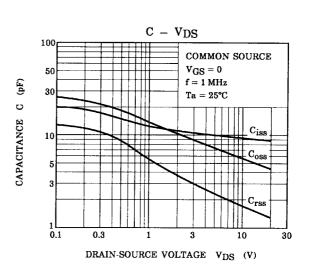




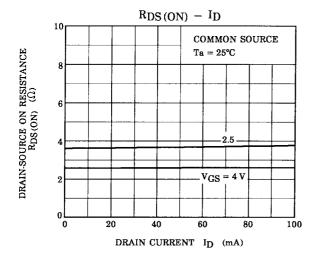


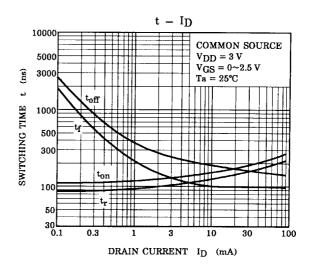


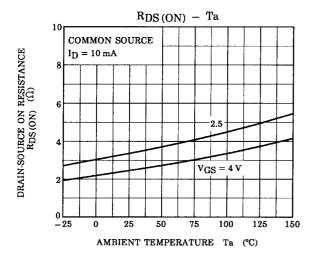


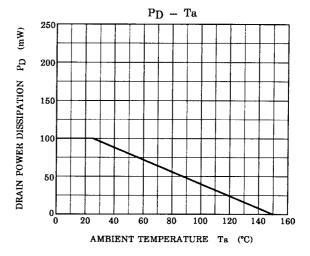


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